

2GB - 240-Pin 2Rx8 Registered ECC LV DDR3 DIMM



Identification

DTM64332B 256Mx72 2GB 2Rx8 PC3L-10600R-9-11-B1 Performance range

Clock / Module Speed / CL-t_{RCD} -t_{RP}

667 MHz / PC3L-10600 / 9-9-9 533 MHz / PC3L-8500 / 8-8-8 533 MHz / PC3L-8500 / 7-7-7 400 MHz / PC3L-6400 / 6-6-6

Description

DTM64332B is a registered 256Mx72 memory module, which conforms to JEDEC's DDR3L, PC3L-10600 standard. The assembly is Dual-Rank. Each Rank is comprised of nine 128Mx8 DDR3 Samsung SDRAMs. One 2K-bit EEPROM is used for Serial Presence Detect and a combination register/PLL, with Address and Command Parity, is also used.

Both output driver strength and input termination impedance are programmable to maintain signal integrity on the I/O signals in a Fly-by topology.

A thermal sensor accurately monitors the DIMM module and can prevent exceeding the maximum operating temperature of 95C.

Features

240-pin JEDEC-compliant DIMM, 133.35 mm wide by 30 mm high

Operating Voltage: VDD = VDDQ = +1.35V (1.283V to 1.45V)

Backward-compatible to VDD = VDDQ = +1.5V ±0.075V

On-board I2C temperature sensor with integrated serial presence-detect (SPD) EEPROM

Data Transfer Rate: 10.6 Gigabytes/sec

Data Bursts: 8 and burst chop 4 mode

ZQ Calibration for Output Driver and On-Die Termination (ODT)

Programmable ODT / Dynamic ODT during Writes

Programmable CAS Latency: 6, 7, 8, and 9

Bi-Directional Differential Data Strobe signals

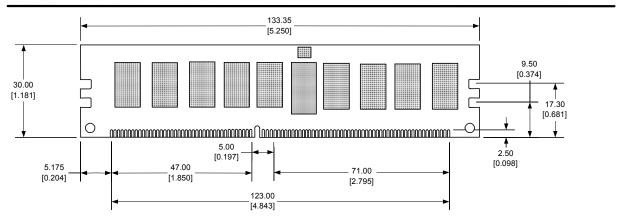
SDRAM Addressing (Row/Col/Bank): 14/10/3

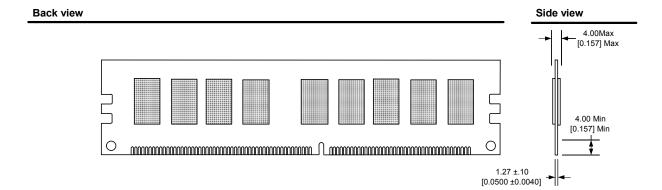
Fully RoHS Compliant

* Not used

					Pin Co	nfigurati	on				Pin De	escription
Front S	ide					Back Sid	е				Name	Function
1 V _{REFDQ}	31 DQ25	61	A2	91	DQ41	121 V _{SS}	151 V _{SS}	181 A1	211	V _{SS}	CB[7:0]	Data Check Bits
2 V _{SS}	32 V _{SS}	62	V_{DD}	92	V_{SS}	122 DQ4	152 DM3	182 V _{DD}	212	DM5	DQ[63:0]	Data Bits
3 DQ0	33 /DQS3	63		93	/DQS5	123 DQ5	153 /TDQS12	183 V _{DD}	213	/TDQS14	DQS[8:0], /DQS[8:0]	Differential Data Strobes
4 DQ1	34 DQS3	64	/CK1*	94	DQS5	124 V _{SS}	154 V _{SS}	184 CK0	214	V_{SS}	DM[8:0]	Data Mask
5 V _{SS}	35 V _{SS}	65	V_{DD}	95	V_{SS}	125 DM0	155 DQ30	185 /CK0	215	DQ46	/TDQS[17:9]	Termination Data Strobes
6 /DQS0	36 DQ26	66		96	DQ42	126 /TDQS9	156 DQ31	186 V _{DD}	216	DQ47	CK[1:0], /CK[1:0]	Differential Clock Inputs
7 DQS0	37 DQ27	67	V_{REFCA}	97	DQ43	127 V _{SS}	157 V _{SS}	187 /Event	217	V_{SS}	CKE[1:0]	Clock Enables
8 V _{SS}	38 V _{SS}	68		98	V_{SS}	128 DQ6	158 CB4	188 A0	218	DQ52	/CAS	Column Address Strobe
9 DQ2	39 CB0	69	VDD	99	DQ48	129 DQ7	159 CB5	189 V _{DD}	219	DQ53	/RAS	Row Address Strobe
10 DQ3	40 CB1	70	A10/AP	100	DQ49	130 V _{SS}	160 V _{SS}	190 BA1	220	V_{SS}	/S[3:0]	Chip Selects
11 V _{SS}	41 V _{SS}	71	BA0	101	V_{SS}	131 DQ12	161 DM8	191 V _{DD}		DM6	WE	Write Enable
12 DQ8	42/DQS8	72	V_{DD}	102	/DQS6	132 DQ13	162 /TTDQS17	192 /RAS	222	/TDQS15	A[15:0]	Address Inputs
13 DQ9	43 DQS8	73	/WE	103	DQS6	133 V _{SS}	163 V _{SS}	193 /S0	223	V_{SS}	BA[2:0]	Bank Addresses
14 V _{SS}	44 V _{SS}	74	/CAS	104	V_{SS}	134 DM1	164 CB6	194 V _{DD}	224	DQ54	ODT[1:0]	On Die Termination Inputs
15 /DQS1		75	V_{DD}	105	DQ50	135 /TDQS10	165 CB7	195 ODT0	225	DQ55	SA[2:0]	SPD Address
16 DQS1	46 CB3	76	/S1	106	DQ51	136 V _{SS}	166 V _{SS}	196 A13	226	V_{SS}	SCL	SPD Clock Input
17 V _{SS}	47 V _{SS}	77	ODT1	107	V_{SS}	137 DQ14	167 NC (TEST)	197 V _{DD}		DQ60	SDA	SPD Data Input/Output
18 DQ10	48 V _{TT}	78	V_{DD}	108	DQ56	138 DQ15	168 /RESET	198 /S3, NC*	228	DQ61	V_{SS}	Ground
19 DQ11	49 V _{TT}	79	/S2, NC*	109	DQ57	139 V _{SS}	169 CKE1	199 V _{SS}	229	V_{SS}	V _{DD}	Power
20 V _{SS}	50 CKE0	80	V_{SS}	110	V_{SS}	140 DQ20	170 V _{DD}	200 DQ36	230	DM7	V _{DDSPD}	SPD EEPROM Power
21 DQ16	51 V _{DD}	81	DQ32	111	/DQS7	141 DQ21	171 A15	201 DQ37	231	/TDQS16	V_{REFDQ}	Reference Voltage for DQ
22 DQ17	52 BA2	82	DQ33	112	DQS7	142 V _{SS}	172 A14	202 V _{SS}	232	V_{SS}	V_{REFCA}	Reference Voltage for CA
23 V _{SS}	53/E _{RR} _O _{UT}	83	V_{SS}	113	V_{SS}	143 DM2	173 V _{DD}	203 DM4	233	DQ62	V_{TT}	Termination Voltage
24 /DQS2	54 V _{DD}	84	/DQS4	114	DQ58	144 /TDQS11	174 A12/ /BC	204 /TQDS13	234	DQ63	/Event	Temperature Sensing
25 DQS2	55 A11	85	DQS4	115	DQ59	145 V _{SS}	175 A9	205 V _{SS}	235	V_{SS}	NC	No Connection
26 V _{SS}	56 A7	86	V_{SS}	116	V_{SS}	146 DQ22	176 V _{DD}	206 DQ38	236	V_{DDSPD}		
27 DQ18	57 V _{DD}	87	DQ34	117	SA0	147 DQ23	177 A8	207 DQ39	237	SA1		
28 DQ19	58 A5	88	DQ35	118	SCL	148 V _{SS}	178 A6	208 V _{SS}	238	SDA		
29 V _{SS}	59 A4	89	V_{SS}	119	SA2	149 DQ28	179 V _{DD}	209 DQ44	239	V_{SS}		
30 DQ24	60 V _{DD}	90	DQ40	120	V_{TT}	150 DQ29	180 A3	210 DQ45	240	V_{TT}		

Front view





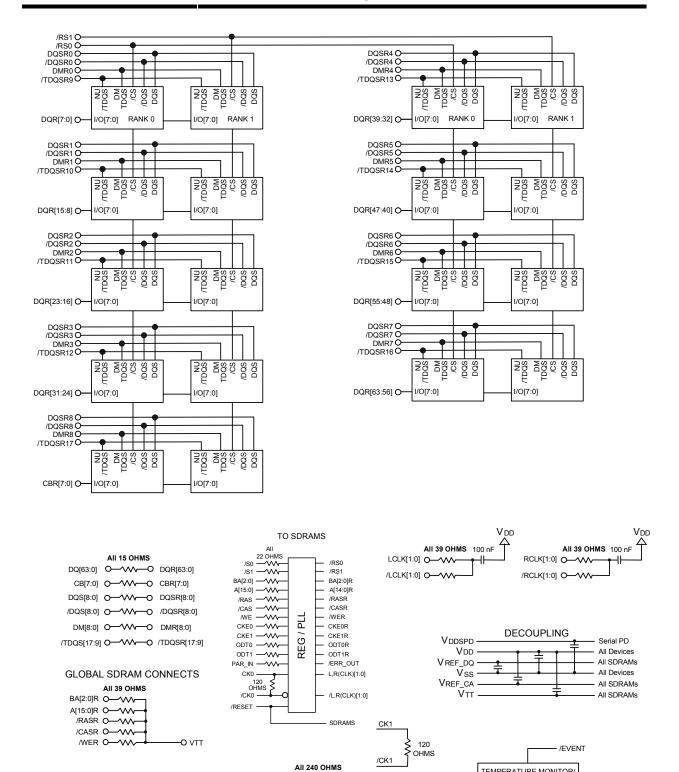
Notes

Tolerances on all dimensions except where otherwise indicated are $\pm .13$ (.005).

All dimensions are expressed: millimeters [inches]



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SERIAL PD

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SA2

SA0



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Absolute Maximum Ratings

(Note: Operation at or above Absolute Maximum Ratings can adversely affect module reliability.)

PARAMETER	Symbol	Minimum	Maximum	Unit
Temperature, non-Operating	T _{STORAGE}	-55	100	С
Ambient Temperature, Operating	T _A	0	70	С
DRAM Case Temperature, Operating	T _{CASE}	0	95	С
Voltage on V _{DD} relative to V _{SS}	V_{DD}	-0.4	1.975	V
Voltage on Any Pin relative to V _{SS}	V _{IN} ,V _{OUT}	-0.4	1.975	V

Notes:

DRAM Operating Case Temperature above 85C requires 2X refresh.

Recommended DC Operating Conditions ($T_A = 0$ to 70 C, Voltage referenced to $V_{ss} = 0$ V)

PARAMETER	Symbol	Operation Voltage	Minimum	Typical	Maximum	Unit	Note
Power Supply Voltage	\/	1.35V	1.283	1.35	1.4500	V	
	V_{DD}	1.5V	1.425	1.5	1.575	V	
I/O Reference Voltage	V_{REFDQ}	1.35V	0.49 V _{DD}	0.50 V _{DD}	0.51 V _{DD}	V	1
	▼ REFDQ	1.5V	- 0.43 V ₀₀	0.00 100	0.01	V	
I/O Reference Voltage	W	1.35V	0.40.\/	0.50 V _{DD}	0.51.\/	V	1
	V_{REFCA}	1.5V	0.49 V _{DD}	0.30 V _{DD}	0.51 V _{DD}		1

Notes:

DC Input Logic Levels, Single-Ended ($T_A = 0$ to 70 C, Voltage referenced to $V_{ss} = 0$ V)

PARAMETER	Symbol	Operation Voltage	Minimum	Maximum	Unit
Logical High (Logic 1)	V _{IH(DC)}	1.35V	V _{REF} + 0.09	V_{DD}	V
		1.5V	V _{REF} + 0.1	V_{DD}	
Logical Low (Logic 0)	V _{IL(DC)}	1.35V	V _{SS}	V _{REF} - 0.09	V
		1.5V	V _{SS}	V _{REF} - 0.1]

AC Input Logic Levels, Single-Ended ($T_A = 0$ to 70 C, Voltage referenced to $V_{ss} = 0$ V)

PARAMETER	Symbol	Operation Voltage	Minimum	Maximum	Unit
Logical High (Logic 1)	V _{IH(AC)}	1.35V	V _{REF} + 0.160	-	V
		1.5V	V _{REF} + 0.175	-	
Logical Low (Logic 0)	V _{IL(AC)}	1.35V	-	V _{REF} - 0.160	V
		1.5V	-	V _{REF} - 0.175	

¹⁾ For Reference $V_{DD}/2 \pm 15$ mV. The value of VREF is expected to equal one-half VDD and to track variations in the VDD DC level. Peak-to-peak noise on VREF may not exceed $\pm 1\%$ of its DC value. For Reference: VREF = VDD/2 ± 15 mV.



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Differential Input Logic Levels ($T_A = 0$ to 70 C, Voltage referenced to $V_{ss} = 0$ V)

PARAMETER	Symbol	Minimum	Maximum	Unit
Differential Input Logic High	V _{IH.DIFF}	+0.200	DC:V _{DD} AC:V _{DD} +0.4	V
Differential Input Logic Low	$V_{IL.DIFF}$	DC:V _{SS} AC:V _{SS} -0.4	-0.200	V
Differential Input Cross Point Voltage relative to VDD/2	V _{IX}	- 0.150	+ 0.150	V

Capacitance (T_A = 25 C, f = 100 MHz)

PARAMETER	Pin	Symbol	Minimum	Maximum	Unit
Input Capacitance, Clock	CK0, /CK0	Сск	1.5	2.5	pF
Input Capacitance, Address	BA[2:0], A[15:0], /RAS, /CAS, /WE	Cı	1.5	2.5	pF
Input Capacitance Control	/S[1:0], CKE[1:0], ODT[1:0]	Cı	1.5	2.5	pF
Input/Output Capacitance	DQ[63:0], CB[7:0] DQS[8:0], /DQS[8:0], DM[8:0], TDQS[17:9]	C _{IO}	2.8	5	pF

DC Characteristics ($T_A = 0$ to 70 C, Voltage referenced to $V_{ss} = 0$ V)

PARAMETER	Symbol	Minimum	Maximum	Unit	Note
Input Leakage Current	I _{IL}	-18	+18	μA	1,2
(Any input 0 V < VIN < VDD)					
Output Leakage Current	I _{OL}	-10	+10	μA	2,3
(0V < VOUT < VDDQ)					

Notes

- 1) All other pins not under test = 0 V
- 2) Values are shown per pin
- 3) DQ, DQS, DQS and ODT are disabled



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 I_{DD} Specifications and Conditions ($T_A = 0$ to 70 C, Voltage referenced to $V_{ss} = 0$ V)

PARAMETER	Symbol	Test Condition	Max \	Unit	
			1.35V	1.5V	
Operating One Bank Active- Precharge Current	I _{DD} 0*	Operating current : One bank ACTIVATE-to-PRECHARGE	998	1120	mA
Operating One Bank Active-Read- Precharge Current	I _{DD} 1*	Operating current : One bank ACTIVATE-to-READ-to-PRECHARGE	1090	1183	mA
Precharge Power- Down Current	I _{DD} 2P	Precharge power down current: (Slow exit)	720	760	mA
Precharge Power- Down Current	I _{DD} 2P	Precharge power down current: (Fast exit)	756	796	mA
Precharge Quiet Standby Current	I _{DD} 2Q	Precharge quiet standby current	806	900	mA
Precharge Standby Current	I _{DD} 2N	Precharge standby current	816	920	mA
Active Power-Down Current	I _{DD} 3P	Active power-down current	756	850	mA
Active Standby Current	I _{DD} 3N	Active standby current	906	1000	mA
Operating Burst Write Current	I _{DD} 4W*	Burst write operating current	1323	1445	mA
Operating Burst Read Current	I _{DD} 4R*	Burst read operating current	1313	1435	mA
Burst Refresh Current	I _{DD} 5*	Refresh current	1473	1585	mA
Self Refresh Current	I _{DD} 6	Self-refresh temperature current: MAX Tc = 85°C	210	210	mA
Operating Bank Interleave Read Current	I _{DD} 7*	All bank interleaved read current	1853	1975	mA

^{*} One module rank in this operation the rest in IDD2P slow exit.



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AC Operating Conditions

PARAMETER	Symbol	Min	Max	Unit
Internal read command to first data	t _{AA}	13.125	20	ns
CAS-to-CAS Command Delay	t _{CCD}	4	-	t _{CK}
Clock High Level Width	t _{CH(avg)}	0.47	0.53	t _{CK}
Clock Cycle Time	t _{CK}	1.5	1.875	ns
Clock Low Level Width	t _{CL(avg)}	0.47	0.53	t _{CK}
Data Input Hold Time after DQS Strobe	t _{DH}	65	-	ps
DQ Input Pulse Width	t _{DIPW}	400	-	ps
DQS Output Access Time from Clock	t _{DQSCK}	-255	+255	ps
Write DQS High Level Width	t _{DQSH}	0.45	0.55	t _{CK(avg)}
Write DQS Low Level Width	t _{DQSL}	0.45	0.55	t _{CK(avg)}
DQS-Out Edge to Data-Out Edge Skew	t _{DQSQ}	-	125	ps
Data Input Setup Time Before DQS Strobe	t _{DS}	30	-	ps
DQS Falling Edge from Clock, Hold Time	t _{DSH}	0.2	-	t _{CK(avg)}
DQS Falling Edge to Clock, Setup Time	t _{DSS}	0.2	-	t _{CK(avg)}
Clock Half Period	t _{HP}	minimum of t_{CH} or t_{CL}	-	ns
Address and Command Hold Time after Clock	t _{IH}	140	-	ps
Address and Command Setup Time before Clock	t _{IS}	65	-	ps
Load Mode Command Cycle Time	t _{MRD}	4	-	t _{CK}
DQ-to-DQS Hold	t _{QH}	0.38	-	t _{CK(avg)}
Active-to-Precharge Time	t _{RAS}	36	9*t _{REFI}	ns
Active-to-Active / Auto Refresh Time	t _{RC}	49.125	-	ns
RAS-to-CAS Delay	t _{RCD}	13.125	-	ns
Average Periodic Refresh Interval 0° C ≤ T _{CASE} < 85° C	t _{REFI}	-	7.8	μs
Average Periodic Refresh Interval 0° C ≤ T _{CASE} < 95° C	t _{REFI}	-	3.9	μs
Auto Refresh Row Cycle Time	t _{RFC}	110	-	ns
Row Precharge Time	t _{RP}	13.125	-	ns
Read DQS Preamble Time	t _{RPRE}	0.9	Note-1	t _{CK(avg)}
Read DQS Postamble Time	t _{RPST}	0.3	Note-2	t _{CK(avg)}
Row Active to Row Active Delay	t _{RRD}	Max(4nCK, 6ns)	-	ns
Internal Read to Precharge Command Delay	t _{RTP}	Max(4nCK, 7.5ns)	-	ns
Write DQS Preamble Setup Time	t _{WPRE}	0.9	-	t _{CK(avg)}
Write DQS Postamble Time	t _{WPST}	0.3	-	t _{CK(avg)}
Write Recovery Time	t _{WR}	15	-	ns
Internal Write to Read Command Delay	t _{WTR}	Max(4nCK, 7.5ns)	-	ns

Notes:

- The maximum preamble is bound by tLZDQS(min) The maximum postamble is bound by tHZDQS(max) 1. 2.



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SERIAL PRESENCE DETECT MATRIX

Byte#	Function.	Value	Hex
	Number of Bytes Used / Number of Bytes in SPD Device / CRC Covera	ge.	
0	Bit 3 ~ Bit 0. SPD Bytes Used -	176	0x92
U	Bit 6 ~ Bit 4. SPD Bytes Total -	256	0,792
	Bit 7. CRC Coverage -	Bytes 0-116	
1	SPD Revision.	Rev. 1.1	0x11
2	Key Byte / DRAM Device Type.	DDR3 SDRAM	0x0B
	Key Byte / Module Type.		
3	Bit 3 ~ Bit 0. Module Type -	RDIMM	0x01
	Bit 7 ~ Bit 4. Reserved -	0	
	SDRAM Density and Banks.		
4	Bit 3 ~ Bit 0. Total SDRAM capacity, in megabits -	1Gb	0x02
	Bit 6 ~ Bit 4. Bank Address Bits -	8 banks	ONOL
	Bit 7. Reserved -	0	
	SDRAM Addressing.		
5	Bit 2 ~ Bit 0. Column Address Bits -	10	0x11
3	Bit 5 ~ Bit 3. Row Address Bits -	14	UXII
	Bit 7, 6. Reserved	0	
	Module Nominal Voltage, VDD.		
	Bit 0. NOT 1.5 V operable -		
	Bit 1. 1.35 V operable -	X	
6	Bit 2. 1.2X V operable -		0x02
0	Bit 3. Reserved -		0.02
	Bit 4. Reserved -		
	Bit 5. Reserved -		
	Bit 6. Reserved -		
_	Module Organization. Bit 2 ~ Bit 0. SDRAM Device Width -	8-Bits	
7	Bit 5 ~ Bit 3. Number of Ranks -	2-Rank	0x09
	Bit 7, 6. Reserved	0	
	Module Memory Bus Width.	~	
	Bit 2 ~ Bit 0. Primary bus width, in bits -	64-Bits	000
8	Bit 4, Bit 3. Bus width extension, in bits -	8-Bits	0x0B
	Bit 7 ~ Bit 5. Reserved -	0	
	Fine Timebase (FTB) Dividend / Divisor.		
9	Bit 3 ~ Bit 0. Fine Timebase (FTB) Divisor	1	0x11
	Bit 7 ~ Bit 4. Fine Timebase (FTB) Dividend	1	
10		1 (MTB =	0x01
10	Medium Timebase (MTB) Dividend.	0.125ns)	UXUI



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11	Medium Timebase (MTB) Divisor.	8 (MTB = 0.125ns)	0x08			
12	SDRAM Minimum Cycle Time (tCKmin).	1.5ns	0x0C			
13	Reserved.	UNUSED	0x00			
	CAS Latencies Supported, Least Significant Byte.					
	Bit 0. CL = 4 -					
	Bit 1. CL = 5 -					
14	Bit 2. CL = 6 -	X	0x3C			
17	Bit 3. CL = 7 -	X	0,30			
	Bit 4. CL = 8 - Bit 5. CL = 9 -	X	_			
	Bit 5. CL = 9 -	^				
	Bit 0. GL = 10 -					
	CAS Latencies Supported, Most Significant Byte.					
	Bit 0. CL = 12 -					
	Bit 1. CL = 13 -					
4-	Bit 2. CL =14 -]			
15	Bit 3. CL = 15 -		0x00			
	Bit 4. CL = 16 -					
	Bit 5. CL = 17 -					
	Bit 6. CL = 18 - Bit 7. Reserved.					
16	Minimum CAS Latency Time (tAAmin).	13.125ns	0x69			
17	Minimum Write Recovery Time (tWRmin).	15.0ns	0x78			
18	Minimum RAS# to CAS# Delay Time (tRCDmin).	13.125ns	0x69			
19	Minimum Row Active to Row Active Delay Time (tRRDmin).	6.0ns	0x30			
20	Minimum Row Precharge Delay Time (tRPmin).	13.125ns	0x69			
	Upper Nibbles for tRAS and tRC.					
21	Bit 3 ~ Bit 0. tRAS Most Significant Nibble -	1	0x11			
	Bit 7 ~ Bit 4. tRC Most Significant Nibble -	1				
22	Minimum Active to Precharge Delay Time (tRASmin), Least Significant Byte.	36.0ns	0x20			
23	Minimum Active to Active/Refresh Delay Time (tRCmin), Least Significant Byte. 49.125ns					
24	Minimum Refresh Recovery Delay Time (tRFCmin), Least Significant Byte.	110.0ns	0x70			
25	Minimum Refresh Recovery Delay Time (tRFCmin), Most Significant Byte.	110.0ns	0x03			
26	Minimum Internal Write to Read Command Delay Time (tWTRmin).	7.5ns	0x3C			
27	Minimum Internal Read to Precharge Command Delay Time (tRTPmin).	7.5ns	0x3C			



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28	Upper Nibble for tFAW.		0x00	
	Bit 3 ~ Bit 0. tFAW Most Significant Nibble -	0	OXOO	
	Bit 7 ~ Bit 4. Reserved -	0		
29	Minimum Four Activate Window Delay Time (tFAWmin), Least Significant Byte.	30.0ns	0xF0	
	SDRAM Optional Features.			
	Bit 0. RZQ / 6 -	Х	0x83	
30	Bit 1. RZQ / 7 -	Х		
	Bit 6 ~ Bit 2. Reserved -			
	Bit 7. DLL-Off Mode Support			
	SDRAM Drivers Supported.			
	Extended Temperature Range -	Х	1	
	Extended Temperature Refresh Rate -			
31	Auto Self Refresh (ASR) -		0x01	
31	On-die Thermal Sensor (ODTS) Readout -			
	Reserved -			
	Reserved -			
	Reserved -			
	Partial Array Self Refresh (PASR) -			
32	Module Thermal Sensor.		0x80	
32	Bit 6 ~ Bit 0. Thermal Sensor Accuracy -	0	0,00	
	Bit 7. Thermal Sensor -	With TS		
	SDRAM Device Type.			
	Bit 6 ~ Bit 0. Non-Standard Device Description -	0	4	
33	Bit 7. SDRAM Device Type -	Std Mono	0x00	
34-59	Reserved	UNUSED	0x00	
	Module Nominal Height.			
60	Bit 4 ~ Bit 0. Module Nominal Height max, in mm -	29 <h<=30< td=""><td rowspan="2">0x0F</td></h<=30<>	0x0F	
	Bit 7 ~ Bit5. Reserved -	0		
	Module Maximum Thickness.			
61	Bit 3 ~ Bit 0. Front, in mm (baseline thickness = 1 mm) -	1 <th<=2< td=""><td rowspan="2">0x11</td></th<=2<>	0x11	
	Bit 7 ~ Bit 4. Back, in mm (baseline thickness = 1 mm) -	1 <th<=2< td=""></th<=2<>		
	Reference Raw Card Used.			
62	Bit 4 ~ Bit 0. Reference Raw Card -	R/C B	0x21	
-	Bit 6, Bit 5. Reference Raw Card Revision -	Rev.1		
	Bit 7. Reserved -	0		
63	gistered) DIMM Module Attributes.			
	Bit 1 ~ Bit 0. # of Registers used on RDIMM -	1 Register	0x05	
	Bit 3 ~ Bit 2. # of Rows of DRAMs on RDIMM -	1 Row		
	Bit 7 ~ Bit 4. Reserved -	0		



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	RDIMM Thermal Heat Spreader Solution.		
64	Bit 6 ~ Bit 0. Heat Spreader Thermal Characteristics -	0	0x00
	·		
	Bit 7. Heat Spreader Solution -	No HS	-
65	Register Manufacturer ID Code, Least Significant Byte (Optional).		0x04
66	Register Manufacturer ID Code, Most Significant Byte (Optional).		0xB3
67	Register Revision Number (Optional).		0x21
68	Register Type.		
	Bit[2-0] Support Device -	SSTE32882	0x00
	Bit[7-3] Reserved -	0	
69	[SSTE32882]: RC1 (MS Nibble) / RC0 (LS Nibble)	UNUSED	0x00
	[SSTE32882]: RC3 (MS Nibble) / RC2 (LS Nibble) - Drive Strength, Command/Address.		
70	Bit 1, Bit 0. RC2/DA3,4 Value	RESERVED	0x50
7.0	Bit 3, Bit 2. RC2/DBA0,1 Value -	RESERVED	0,00
	Bit 5, Bit 4. RC3/DA4,3 value, Command/Address A Outputs -	Moderate	
	Bit 7, Bit 6. RC3/DBA0,1 value, Command/Address B Outputs -	Moderate	
	[SSTE32882]: RC5 (MS Nibble) / RC4 (LS Nibble) - Drive Strength, Control and Clock.		
71	Bit 1, Bit 0. RC4/DA3,4 Control Signals, A Outputs	Light	0x00
	Bit 3, Bit 2. RC4/DBA0,1 Control Signals, B Outputs -	Light	
	Bit 5, Bit 4. RC5/DA4,3 value, Y1/Y1# and Y3/Y3# Clock Outputs - Bit 7, Bit 6. RC5/DBA0,1 value, Y0/Y0# and Y2/Y2# Clock Outputs -	Light Light	
72	[SSTE32882]: RC7 (MS Nibble) / RC6 (LS Nibble).	UNUSED	0x00
73	[SSTE32882]: RC9 (MS Nibble) / RC8 (LS Nibble).	UNUSED	0x00
74	[SSTE32882]: RC11 (MS Nibble) / RC10 (LS Nibble).	UNUSED	0x00
75	[SSTE32882]: RC13 (MS Nibble) / RC12 (LS Nibble).	UNUSED	0x00
76	[SSTE32882]: RC15 (MS Nibble) / RC14 (LS Nibble).	UNUSED	0x00
77- 112	Module-Specific Section	UNUSED	0x00
113	Module-Specific Section.	UNUSED	0x00
114- 116	Module-Specific Section	UNUSED	0x00
117	Module Manufacturer ID Code, Least Significant Byte		0x80
118	Module Manufacturer ID Code, Most Significant Byte		0xCE
119	Module Manufacturing Location		0x01
120, 121	Module Manufacturing Date		0x20
122- 125	Module Serial Number		0x20
126	Cyclical Redundancy Code (CRC).	CRC	0x66
127	Cyclical Redundancy Code (CRC).	CRC	0x11



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128	Module Part Number	М	0x4D
129	Module Part Number	3	0x33
130	Module Part Number	9	0x39
131	Module Part Number	3	0x33
132	Module Part Number	В	0x42
133	Module Part Number	5	0x35
134	Module Part Number	6	0x36
135	Module Part Number	7	0x37
136	Module Part Number	3	0x33
137	Module Part Number	G	0x47
138	Module Part Number	В	0x42
139	Module Part Number	0	0x30
140	Module Part Number	-	0x2D
141	Module Part Number	Υ	0x59
142	Module Part Number	Н	0x48
143	Module Part Number	9	0x39
144, 145	Module Part Number		0x20
146, 147	Module Revision Code	UNUSED	0x00
148	DRAM Manufacturer ID Code, Least Significant Byte		0x80
149	DRAM Manufacturer ID Code, Most Significant Byte		0xCE
150- 175	Manufacturer's Specific Data	UNUSED	0x00
176- 255	Open for customer use	UNUSED	0x00

Note: Serial Presence Detect shown for reference only. Bytes # 119 - 125, 146,147,150 - 255 value may vary.



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